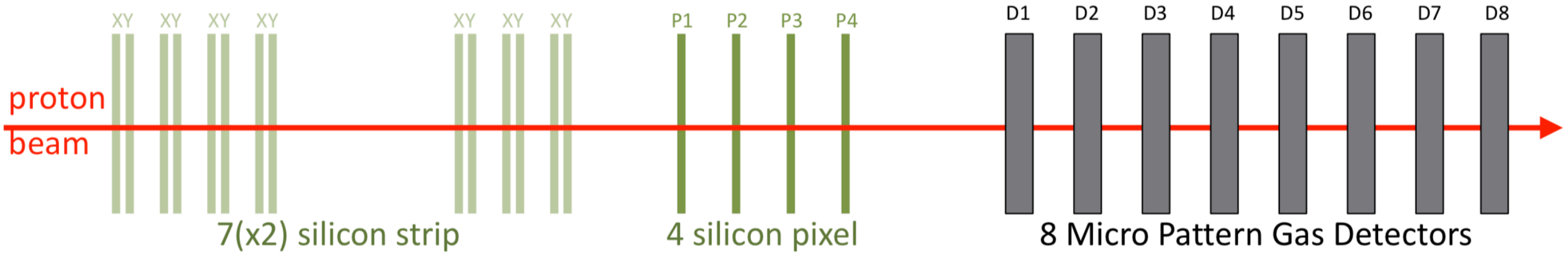
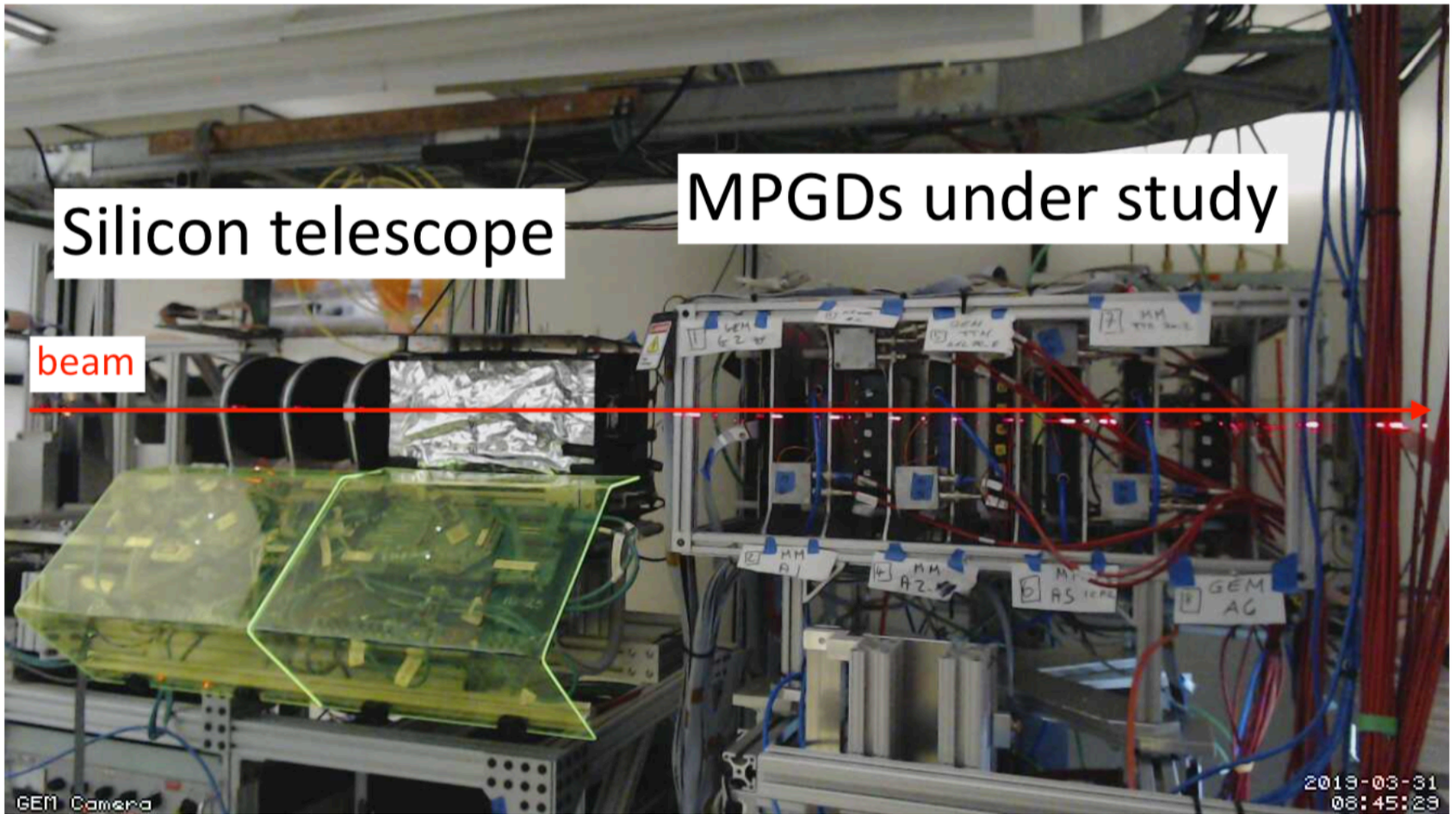
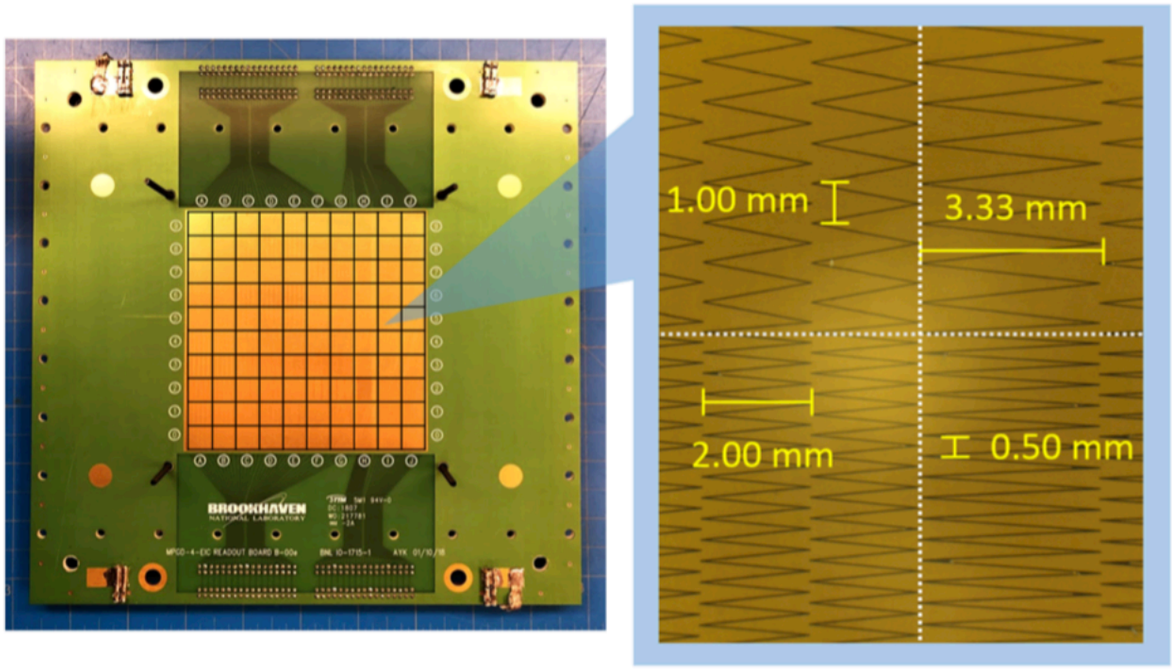
MPGD test beam2019 analysis

Experimental set up

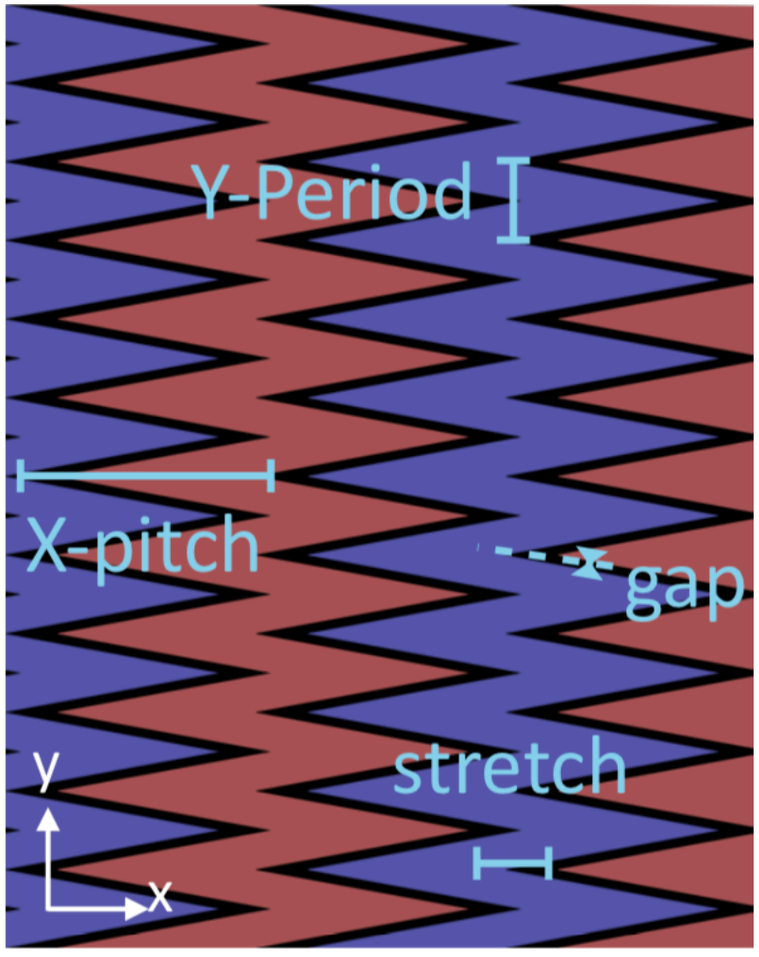




Zigzags pads and avalanche technologies used

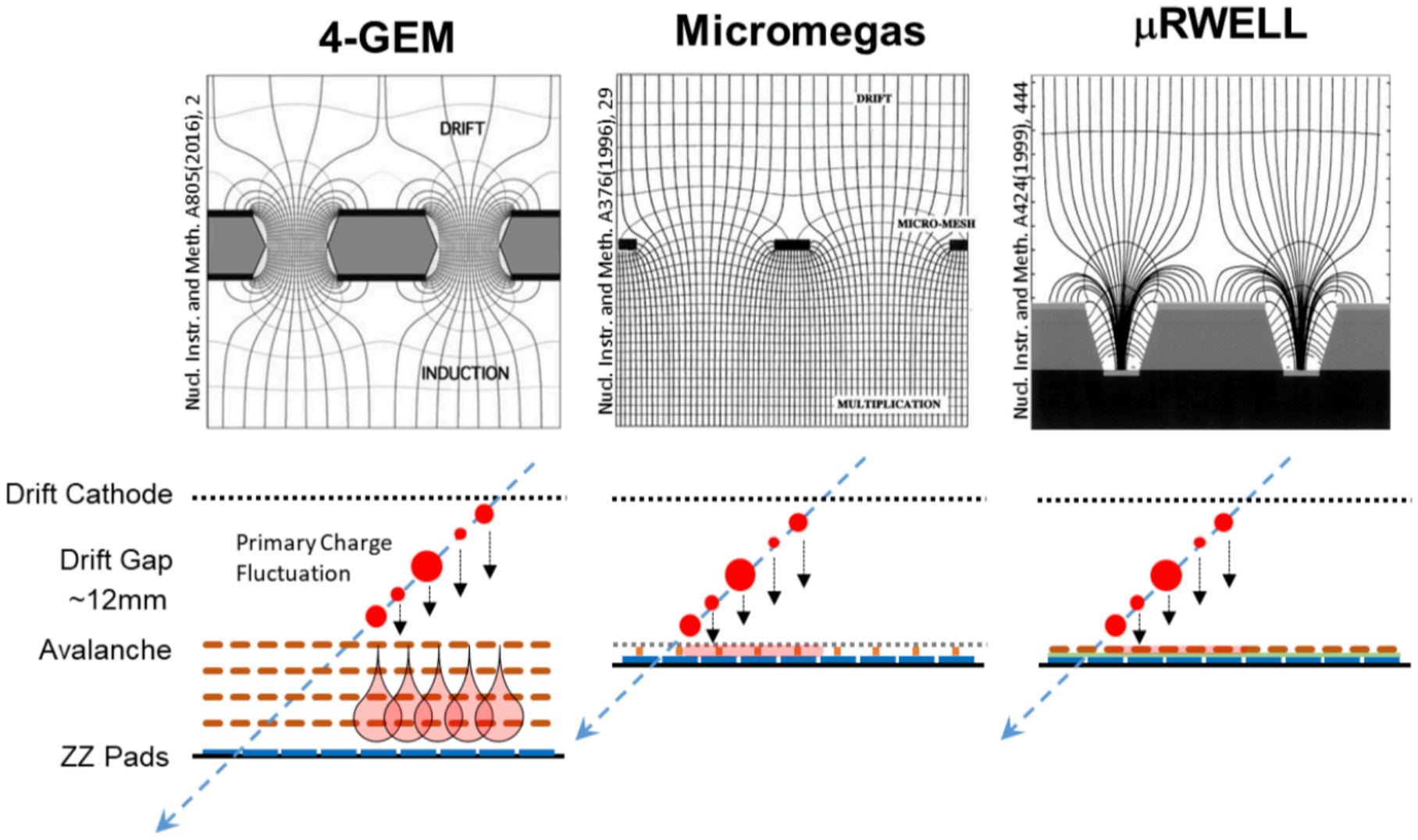


Board



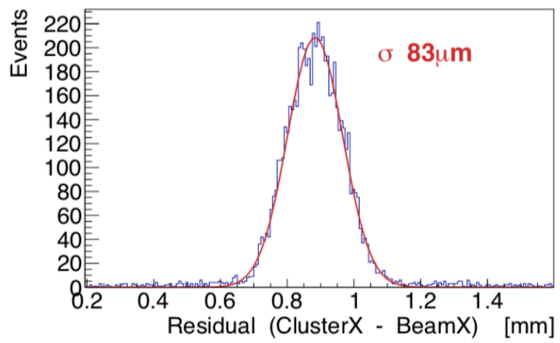
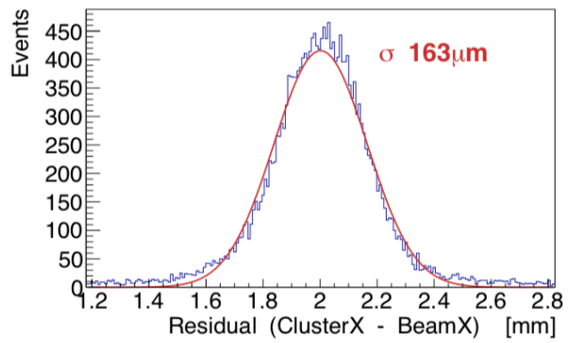
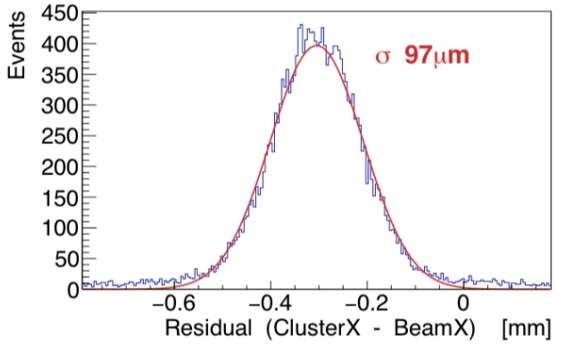
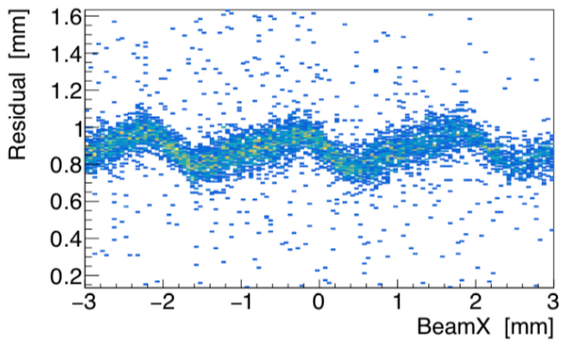
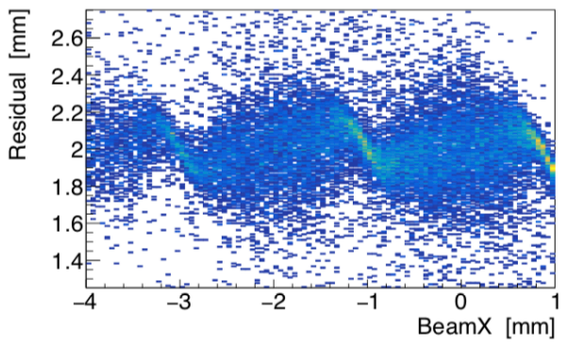
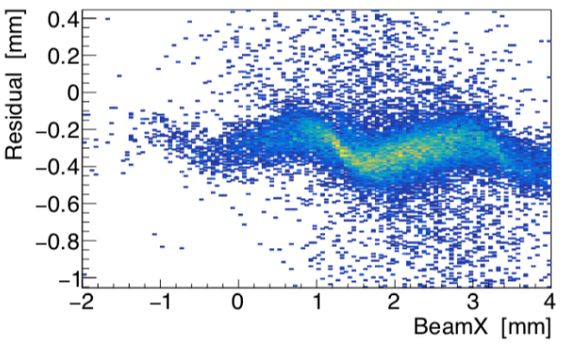
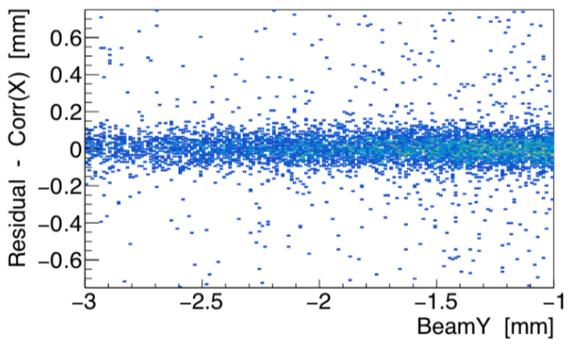
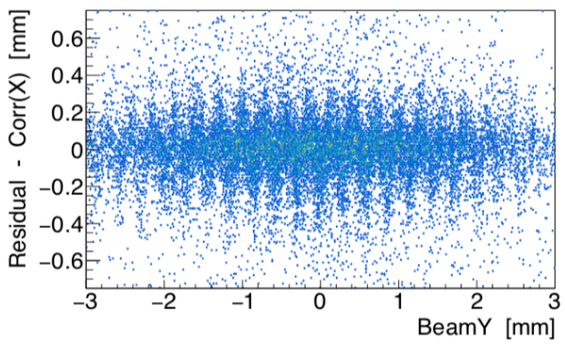
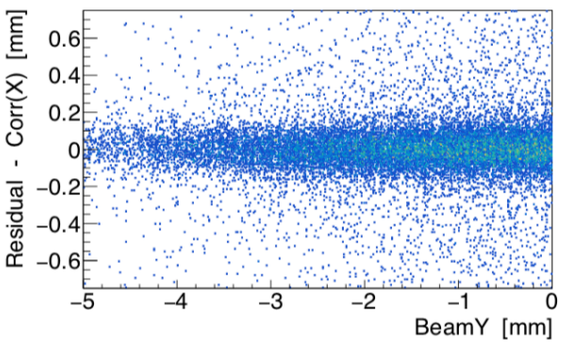
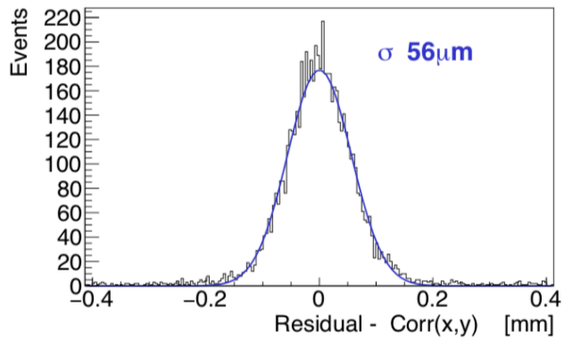
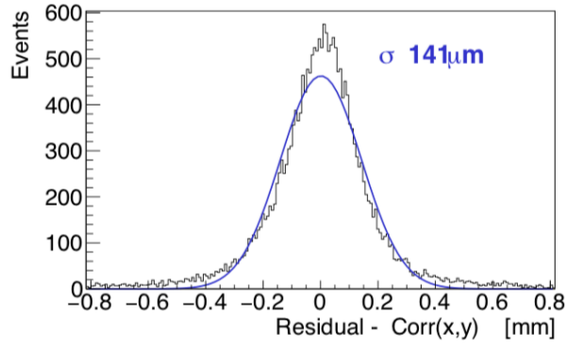
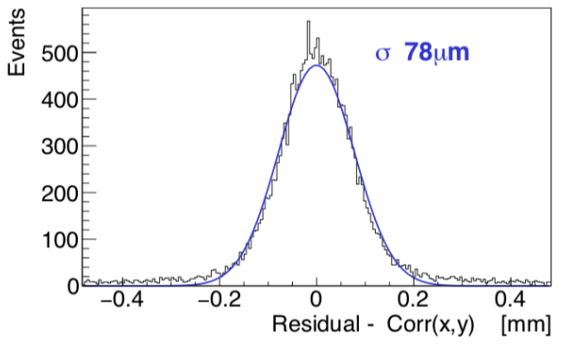
Geometry parameters

Zigzags pads and avalanche technologies used

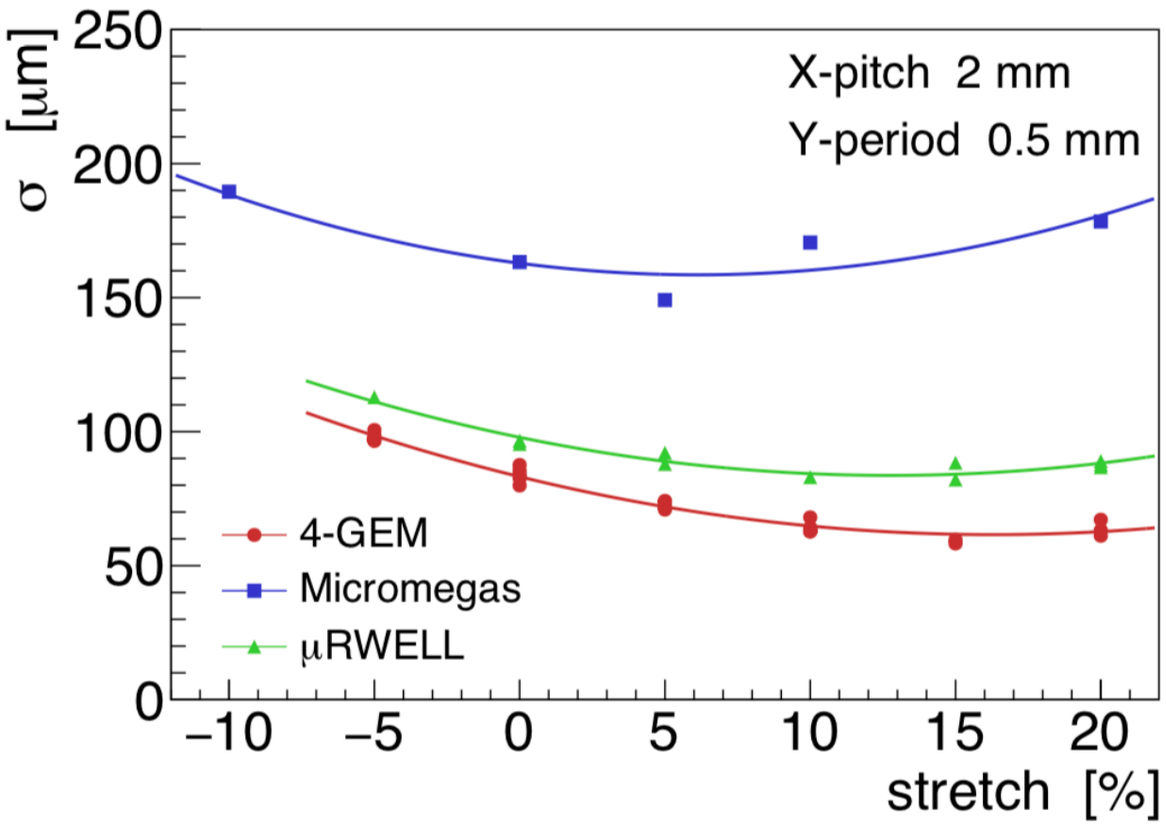


Testbeam data comparative analysis

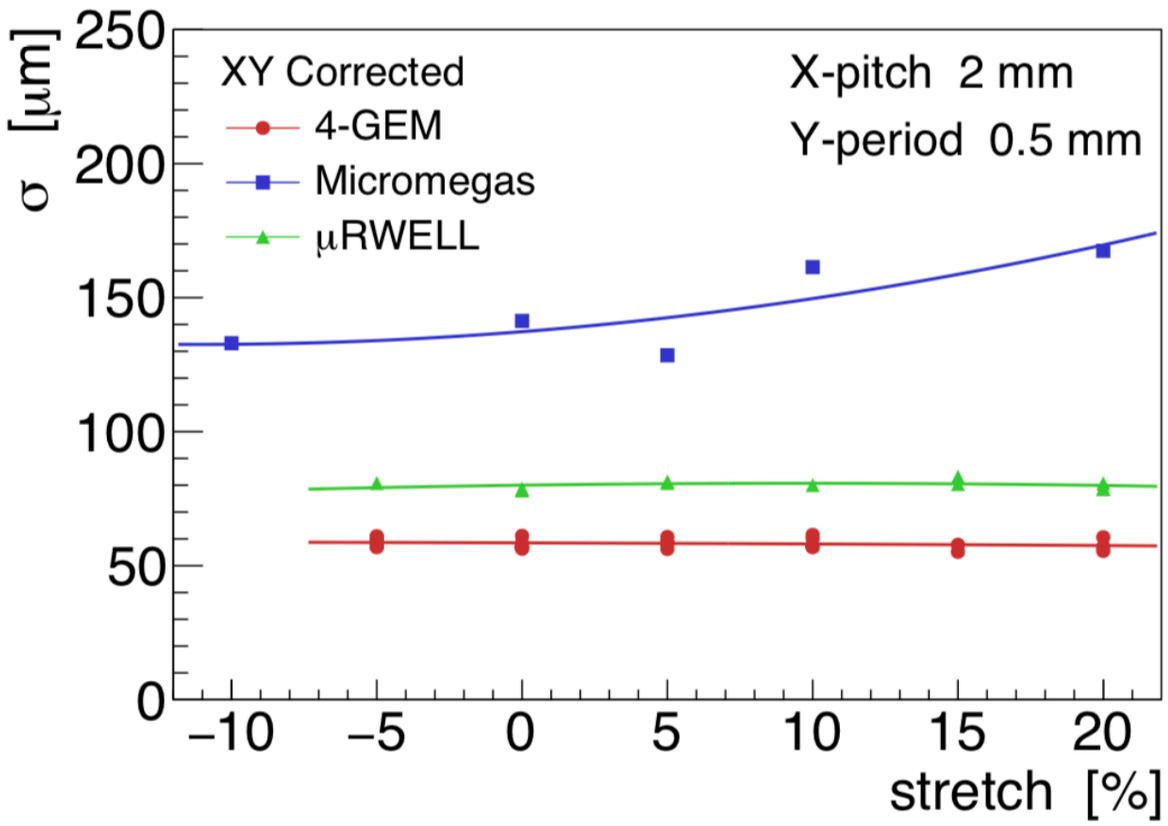
X-pitch=2mm
Y-period=0.5mm
Stretch 0 %

	4-GEM	Micromegas	µRWELL
Raw residuals			
Residuals scan in X direction before Non linearity correction			
Residuals scan in Y direction after correction of no-linearity in X			
Residuals after X and Y corrections			

Study of residual dependance of zigzag geometry



Before corrections

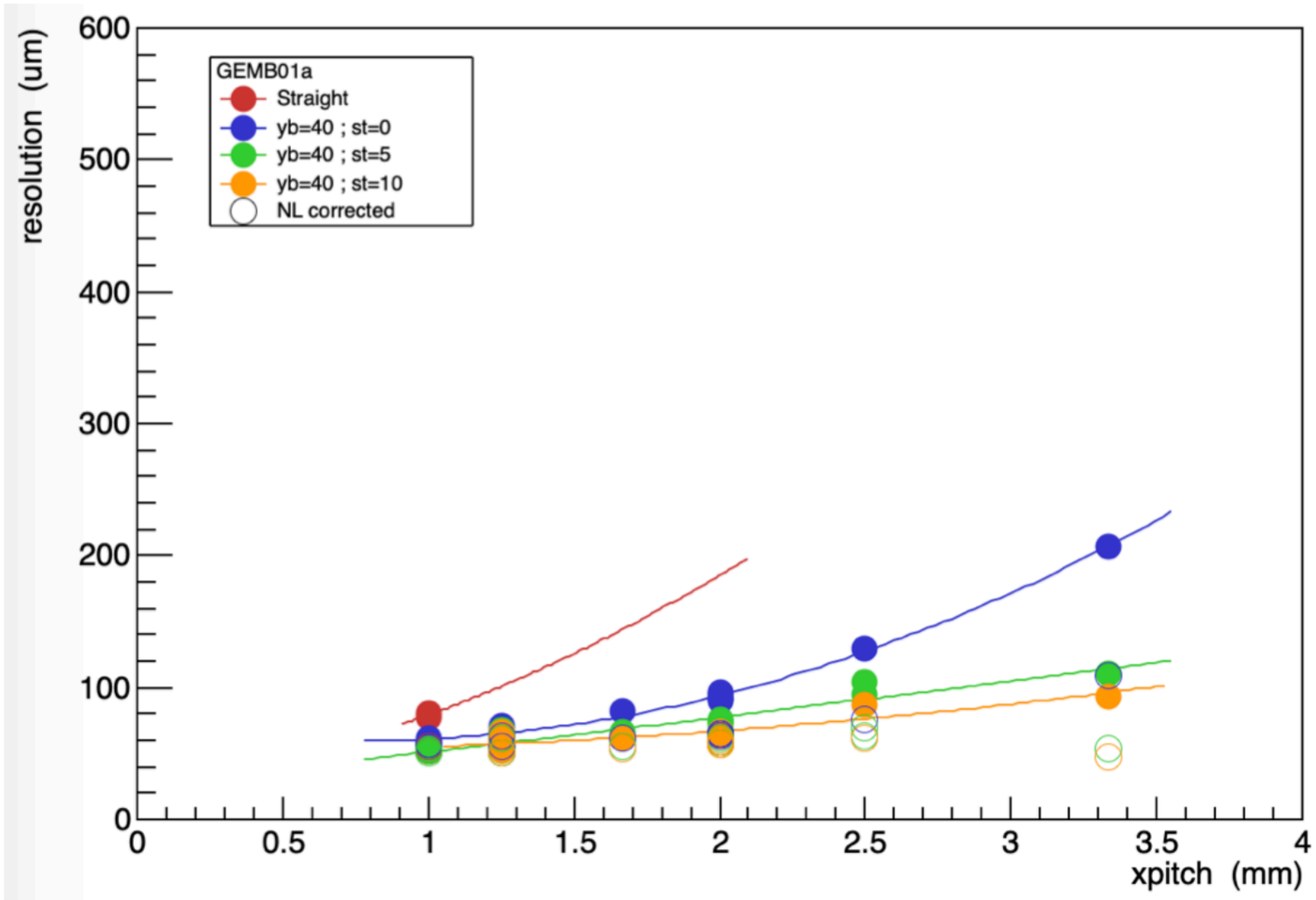


After corrections

Raw residual (Cluster X - Silicon X) width as a function of stretch

detectors working in $ArCO_2$\{70-30\}.

Study of residual dependance of zigzag geometry



No dependance of the xpitch size after NL corrections

On going work

-Investigation the response of rectangular vs zigzag pads